

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10786609	NAKANO ET AL.
	<b>Examiner</b> Nguyen, Jennifer T	<b>Art Unit</b> 2629

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
345	93-96,87,89-92,89,100,204,212,690-692	8/29/07	JN

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East search, PAJ,EPO, US-PAT, PG-PUB, DERWENT	8/29/07	JN

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>